

2SC3311, 2SC3311A**Silicon NPN Epitaxial Planar Type**

For low-frequency amplification

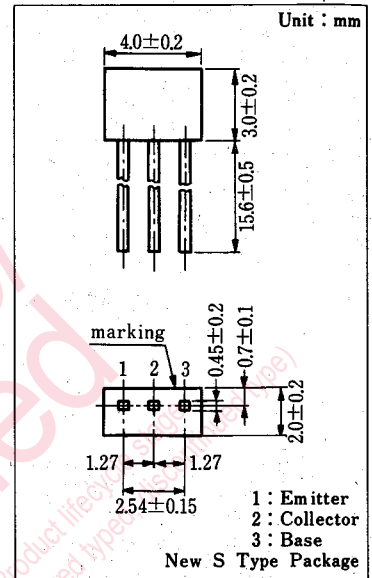
Complementary pair with 2SA1309 and 2SA1309A

■ Features

- Ideal for high-density mounting
- Automatic insertion by radial taping possible

■ Absolute Maximum Ratings (Ta=25°C)

Item	Symbol	Value	Unit
Collector-Base Voltage	2SC3311	30	V
	2SC3311A	60	
Collector-Emitter Voltage	2SC3311	25	V
	2SC3311A	50	
Emitter-Base Voltage	VEBO	7	V
Peak Collector Voltage	ICP	200	mA
Collector Current	IC	100	mA
Collector Power Dissipation	PC	300	mW
Junction Temperature	Tj	150	°C
Storage Temperature	Tstg	-55 ~ +150	°C

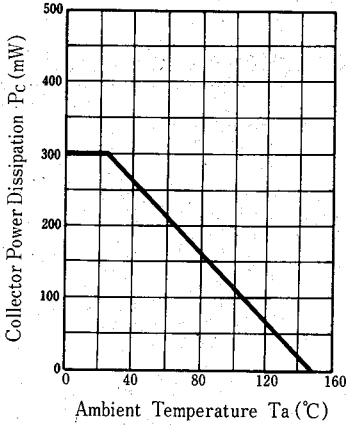
■ Package Dimensions**■ Electrical Characteristics (Ta=25°C)**

Item	Symbol	Condition	min.	typ.	max.	Unit
Collector Cutoff Current	ICBO	V _{CB} =10 V, I _E =0			0.1	μA
	ICEO	V _{CE} =10 V, I _B =0			1	μA
Collector-Base Voltage	VCBO	I _C =10 μA, I _E =0	30			V
			60			
Collector-Emitter Voltage	V _{CEO}	I _C =2 mA, I _B =0	25			V
			50			
Emitter-Base Voltage	VEBO	I _E =10 μA, I _C =0	7			V
DC Current Gain	h _{FE} *	V _{CE} =10 V, I _C =2 mA	160		460	
Collector-Emitter Saturation Voltage	V _{CE(sat)}	I _C =50 mA, I _B =5 mA			0.3	V
Transition Frequency	f _T	V _{CB} =10V, I _E =-1mA, f=200MHz		150		MHz
Collector Output Capacitance	C _{ob}	V _{CB} =10 V, I _E =0, f=1 MHz		3.5		pF

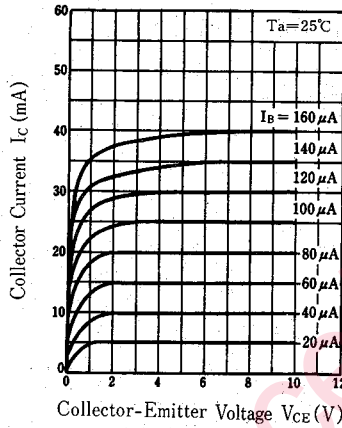
*h_{FE} Ranking

Rank	Q	R	S
h _{FE}	160 ~ 260	210 ~ 340	290 ~ 460

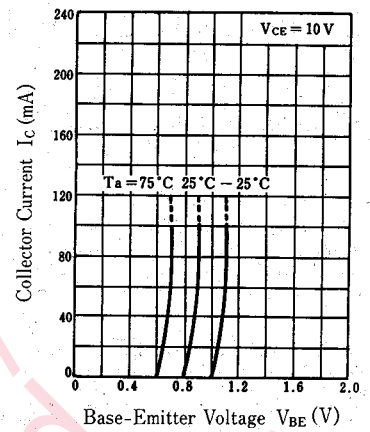
$P_c - T_a$



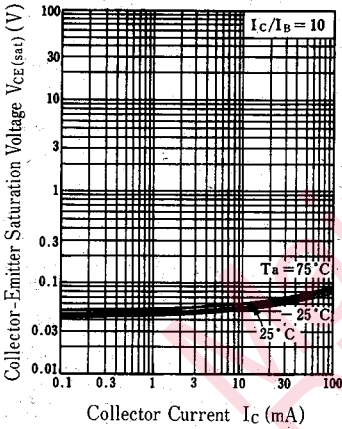
$I_c - V_{CE}$



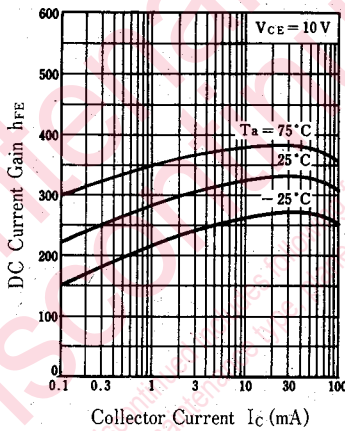
$I_c - V_{BE}$



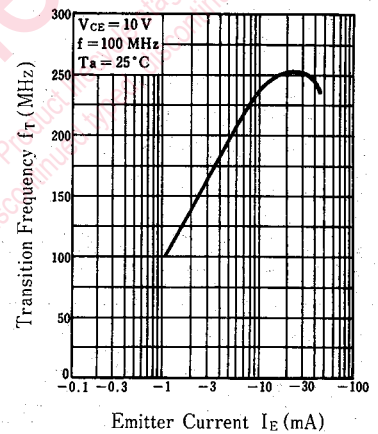
$V_{CE(sat)} - I_c$



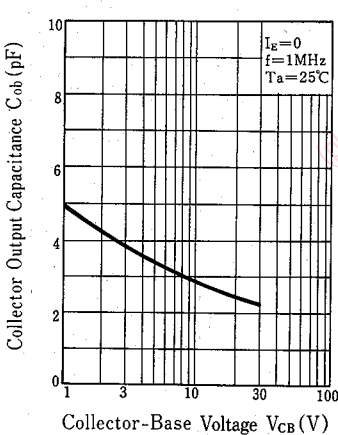
$h_{FE} - I_c$



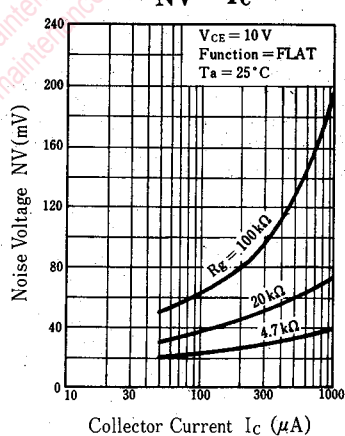
$f_T - I_E$



$C_{ob} - V_{CB}$



$NV - I_c$



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